

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	128241	glass near substrate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:37
L2	1255	(particle or defect or flaw) near3 1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 15:15
L3	90	2 near3 (measur\$5 or detect\$3 or determin\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:38
L4	53338	(mov\$3 or shift\$3 or scan\$4) near3 camera	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 15:23
L5	9	3 and 4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 15:29
L6	19	(unit near area) near3 1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:20
L7	23	3 and camera	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:24
L8	887	scan\$4 near3 1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:24

L9	45	2 and 8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:33
L10	813	250/559.4.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:39
L11	226	250/559.41.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:08
L12	358	250/559.42.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:00
L13	516	250/559.44.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:33
L14	694	250/559.45.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:33
L15	475	250/559.46.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:21
L16	87	250/559.47.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:33

L17	191	250/559.48.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:36
L18	442	356/239.1.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 17:30
L19	113	356/239.2.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:37
L20	78	356/239.7.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:37
L21	193	356/237.3.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/21 16:37
L22	19	((glass near substrate) near3 (particle or defect or flaw)).clm.	US-PGPUB	OR	ON	2005/08/21 17:37
L23	4	(22 near3 (measur\$5 or detect\$3 or determin\$3)).clm.	US-PGPUB	OR	ON	2005/08/21 17:39